

Test Report

Report No.: EED32R804013E

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Client : Shenzhen WELLAUTO technology CO., LTD
Address : Room 402 & 405, Building C, Fenda High-Tech Park, Sanwei Community,
Hangcheng Street, Bao'an District, Shenzhen

Description of the submitted sample(s):

Product : IP67 Fieldbus Series Products
Model/Type reference : AUPN 8AOB, AUPN OA8B, AUEC 8A0B, AUPN OA8B,
AUIO 16DIOP-TE, AUIO 16DIOP-T, AUIO8AIH-BUS,
AUIO 16DION-TE, AUIO 16DION-T, AUPN 16DIOP
Ratings : DC24V
Test Item : Electrical fast transients/burst (EFT/B)
Voltage dips and interruptions
State of Sample(s) : Normal
Sample Quantity : 10pcs
Manufacturer : Shenzhen WELLAUTO technology CO., LTD
Sample Received Date : Apr. 01, 2025
Sample tested Date : Apr. 01, 2025
Test Requested : IEC 61000-4-4:2012, IEC 61000-4-29:2000
And customer requirements

Test Results: Pass.

Compiled by:

Leo Deng

Reviewed by:

Alan - Chen

Approved by:

David Wang

Date of Issue:

Apr. 07, 2025

David Wang

Check No.: 1505250325

Centre Testing International Group Co., Ltd.

Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong,
China



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1. TEST SUMMARY

The Product has been tested according to the following specifications:

Standard	Test Item	Test Result
IEC 61000-4-4:2012	Electrical fast transients/burst (EFT/B)	Pass
IEC 61000-4-29:2000	Voltage dips and interruptions	Pass

2. TEST MODE DESCRIPTION

Test Mode	Test Status
①	Working

3. SUPPORT EQUIPMENT

No.	Device Type	Brand	Series No.	Model	Data Cable	Power Cord
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4. EQUIPMENT LIST

Shielding Room No. 1_Hongwei-Electrical fast transients/burst (EFT/B)				
Equipment	Manufacturer	Model	Series No.	Due Date
Electric fast transient pulse group simulator	3ctest	EFT 600T	ES02700092300 2	04/27/2025
Capacitive coupling clamp	3ctest	CCC100	CCC22090019	12/29/2025

Shielding Room No. 2_Hongwei-Voltage dips and interruptions				
Equipment	Manufacturer	Model	Series No.	Due Date
Power supply	california instrument	15003ix-CTS-400-413-EOS3-LF	1726A00002	05/30/2025
Electronic switch	california instrument	EOS3-230	1726A00001	09/18/2025
Software-AC Source Cl GuiSII	California instrument	--	3.2.0	--

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5. IMMUNITY TEST

Performance Criteria	
CRITERION A	Normal performance within limits specified by the manufacturer, requestor or purchaser;
CRITERION B	Temporary loss of function or degradation of performance which ceases after the disturbance, without operator intervention;
CRITERION C	Temporary loss of function or degradation of performance, the correction of which requires operator intervention;
CRITERION D	Loss of function or degradation of performance which is not recoverable, owing to damage to hardware or software, or loss of data.

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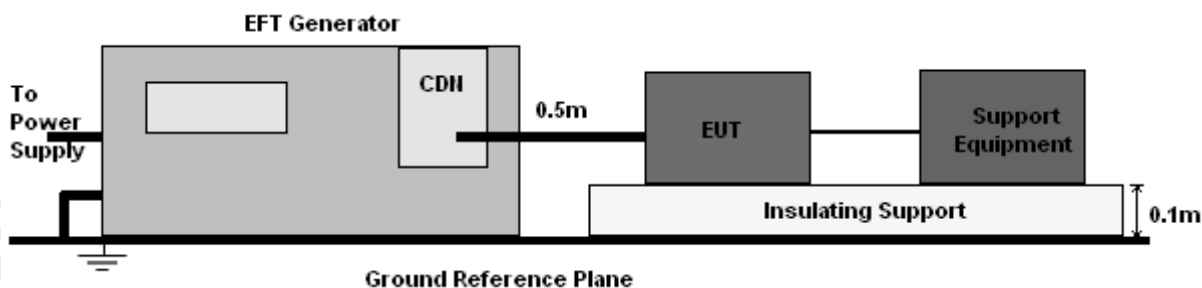
6. ELECTRICAL FAST TRANSIENTS (EFT)

6.1 Test Condition

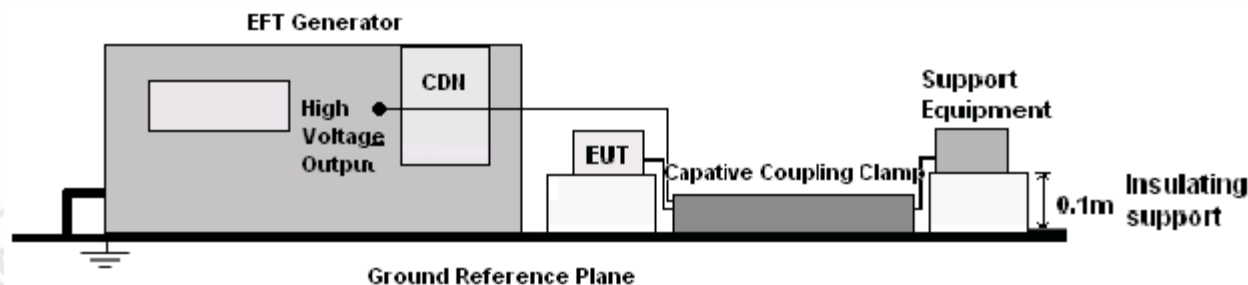
Test Standard	: IEC 61000-4-4:2012
Test Port	: input DC mains power port / Signal Port
Impulse Wave-shape	: 5/50 ns
Frequency	: 5kHz
Burst Period	: 300ms
Burst duration	: 15ms
Duration	: 2Min

6.2 Test Setup

For input DC mains power port:



For signal / telecommunication port:



6.3 Test Procedure

- The product and support units were located on a non-conductive table above ground reference plane.
- A 0.5m-long power cord was attached to product during the test.

6.4 TEST Result

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Product	:	IP67 Fieldbus Series Products		
Model/Type reference	:	AUPN 8AOB, AUPN OA8B, AUPEC 8A0B, AUPN OA8B, AUIO 16DIOP-TE, AUIO 16DIOP-T, AUIO8AIIH-BUS, AUIO 16DION-TE, AUIO 16DION-T, AUPN 16DIOP		
Power	:	DC 24V	Temperature	: 22℃
Mode	:	①	Humidity	: 45%R.H.
Press	:	101kPa		

Coupling	Voltage(kV)	Polarity	Performance Criterion	Test Result
DC mains power port	4	±	B	B*
Signal Port	4	±	B	B*

Remark*: The communication was interrupted during the test, but it can recover by itself after testing.

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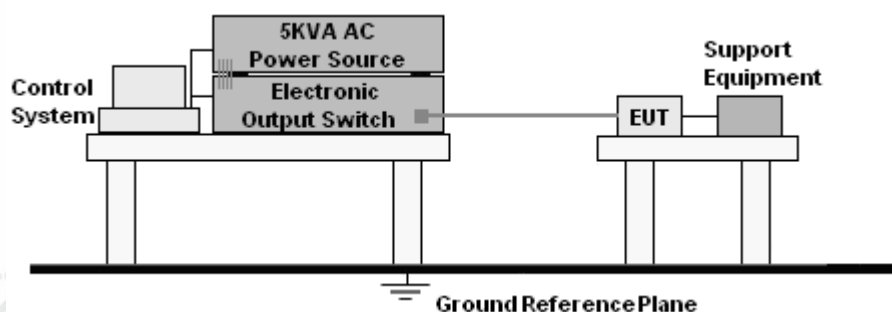
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7. VOLTAGE DIPS AND INTERRUPTIONS

7.1 Test Condition

Test Standard : IEC 61000-4-29:2000
Test Port : Input a.c. power port
Phase angle : /

7.2 Test Setup



7.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground floor.
- Set the parameter of tests and then perform the test software of test simulator.
- Observe the product status and record the product's performance during and after test.

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7.4 Test Result

Product	:	IP67 Fieldbus Series Products		
Model/Type reference	:	AUPN 8AOB, AUPN OA8B, AUEC 8A0B, AUPN OA8B, AUIO 16DIOP-TE, AUIO 16DIOP-T, AUIO8AIIH-BUS, AUIO 16DION-TE, AUIO 16DION-T, AUPN 16DIOP		
Power	:	DC 24V	Temperature	: 23℃
Mode	:	①	Humidity	: 50%R.H.
Press	:	101kPa		

Voltage Dips:

Test Level% UT	Reduction(%)	Time of duration	Number of cycles 60Hz	Performance Criterion	Test Result
0	100	50ms	/	B	B*
0	100	2ms	/	A	A

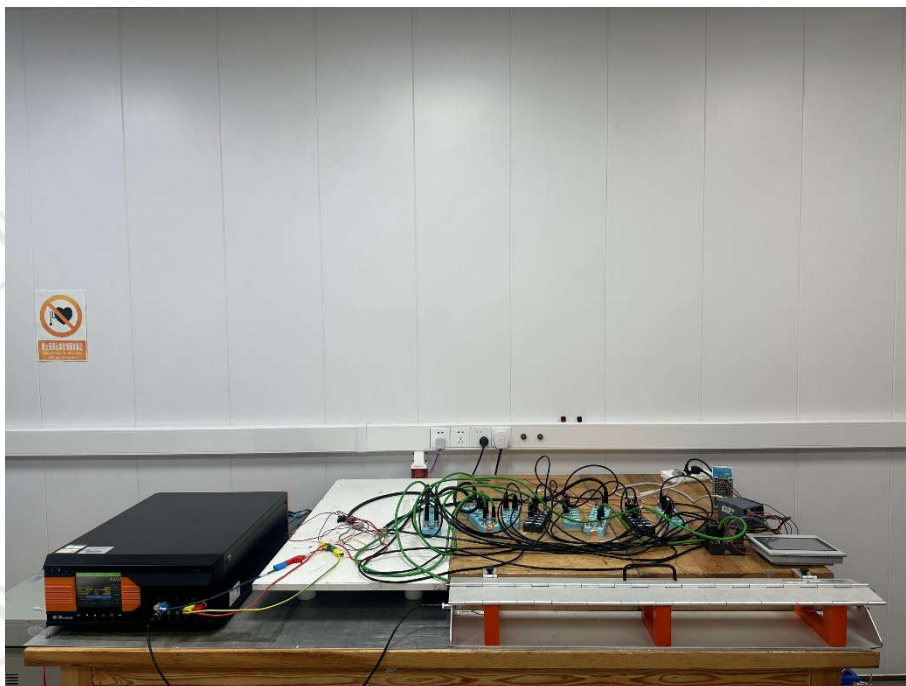
Remark*: The product stopped working during the test, but it can recover by itself after testing.

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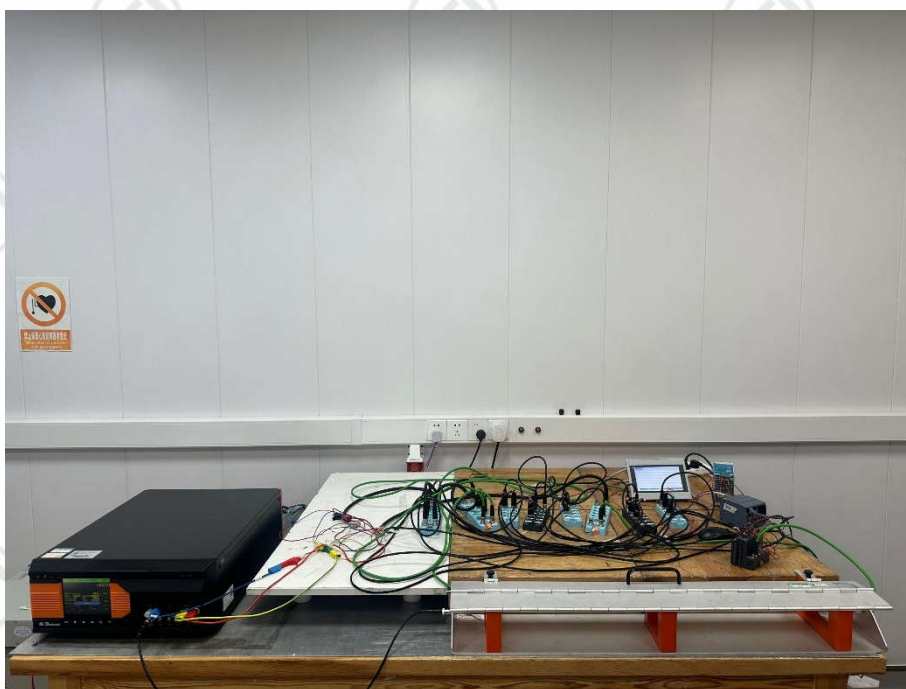
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TEST PHOTO



Electrical fast transients burst Test Setup-1

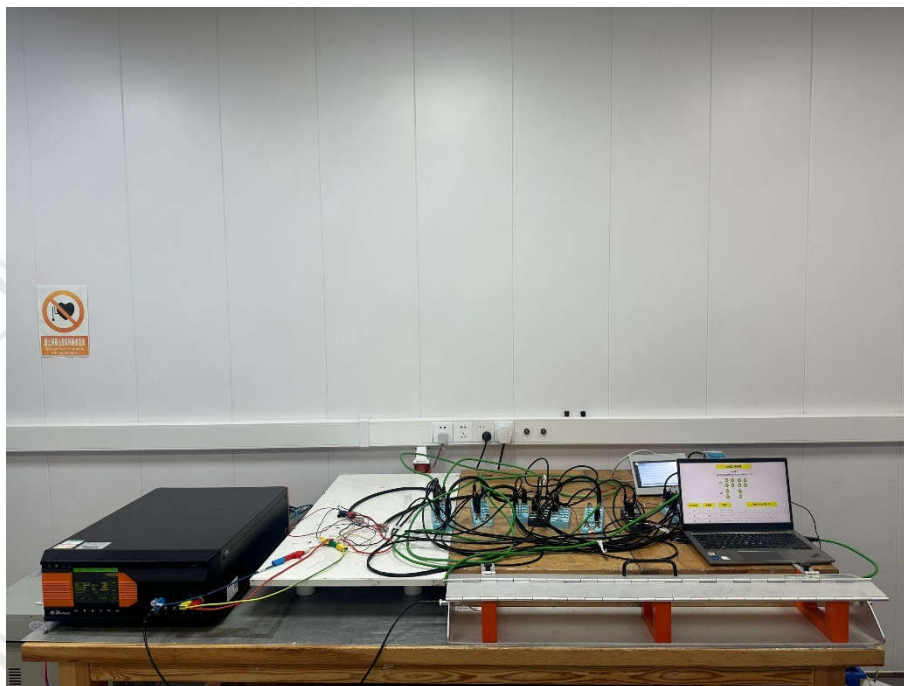


Electrical fast transients burst Test Setup-2

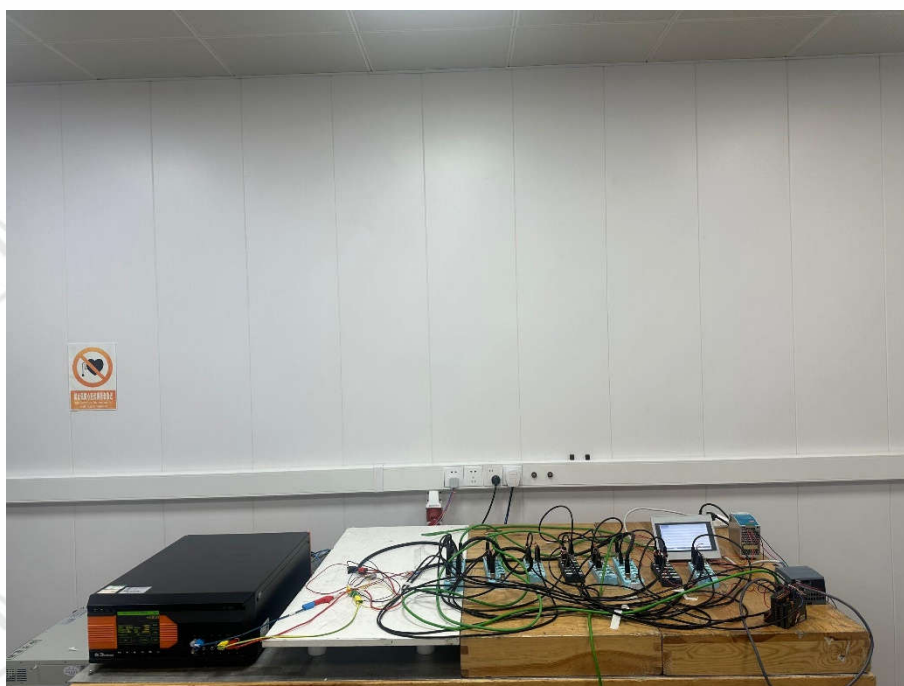
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Electrical fast transients burst Test Setup-3



Electrical fast transients burst Test Setup-4

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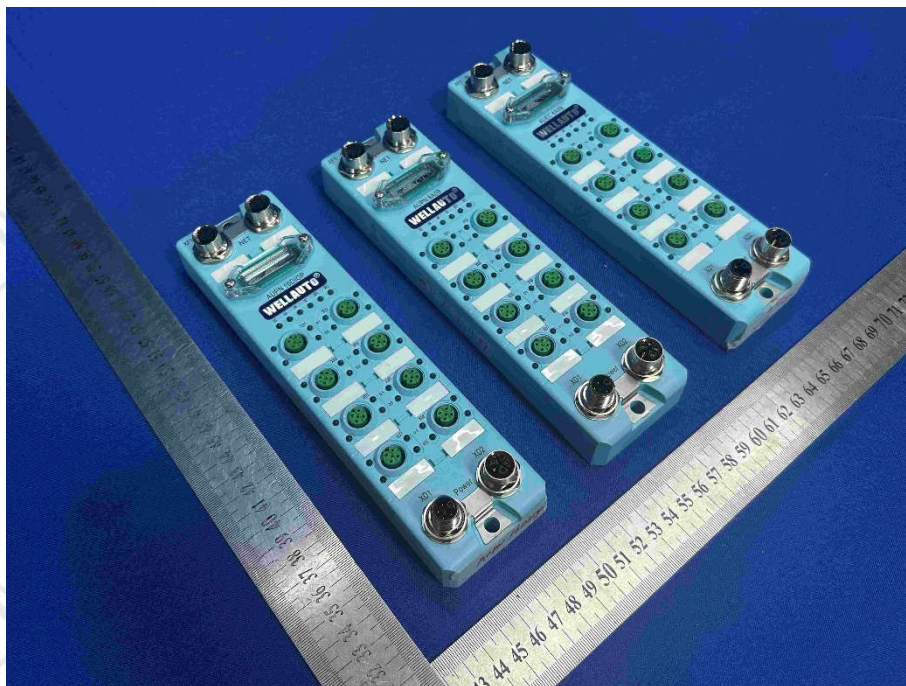
Voltage dips and interruptions Test Setup-1

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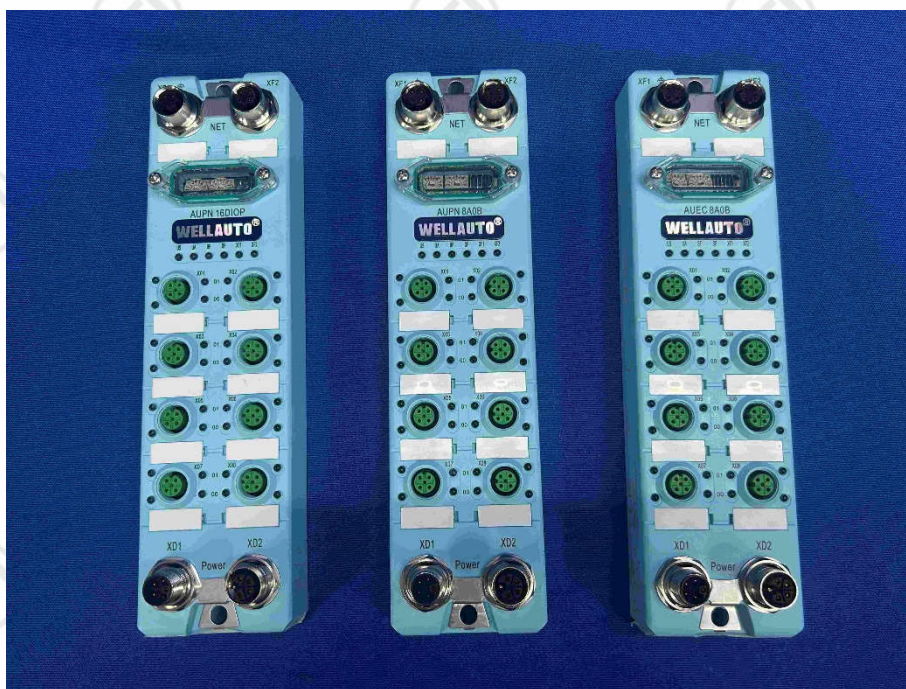
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PRODUCT PHOTO



View Of Product-01

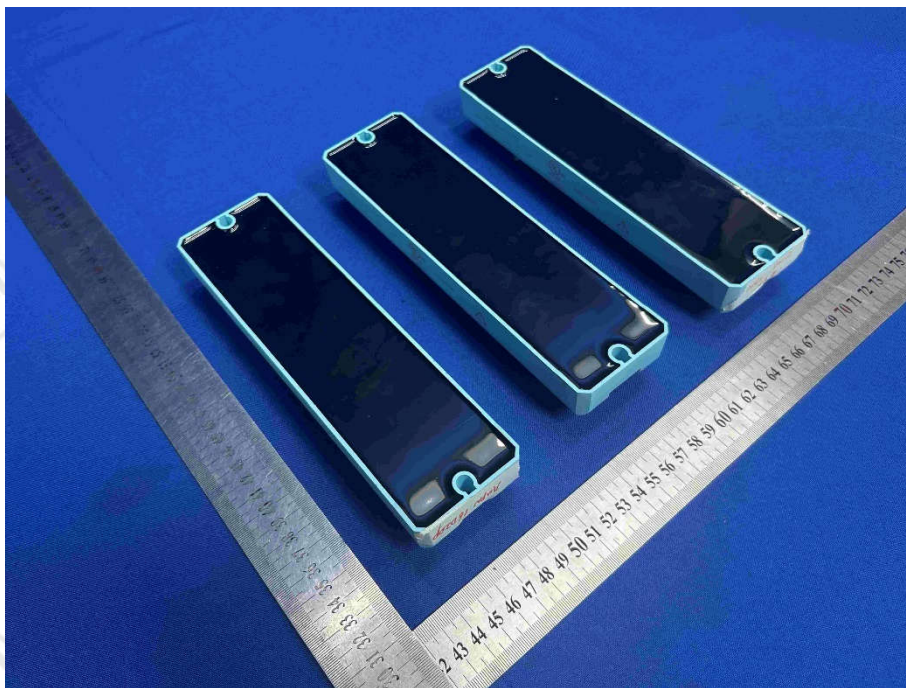


View Of Product-02

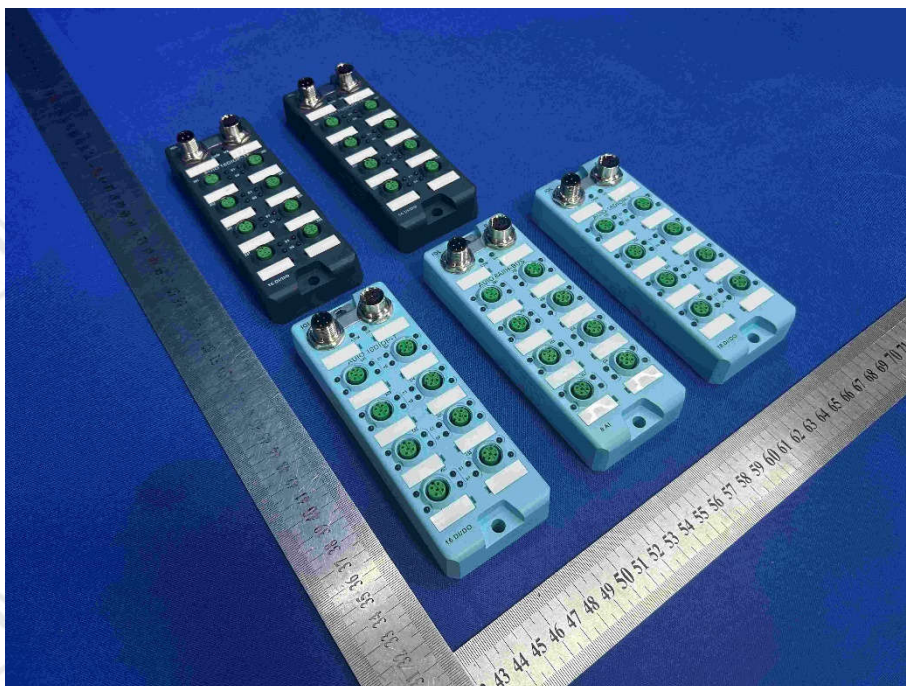
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View Of Product-03

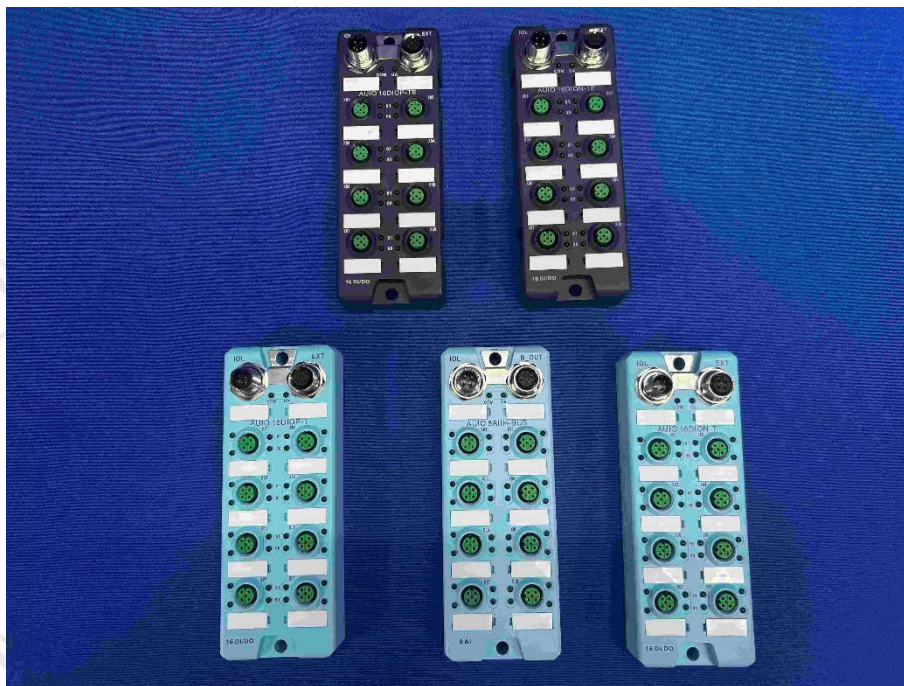


View Of Product-04

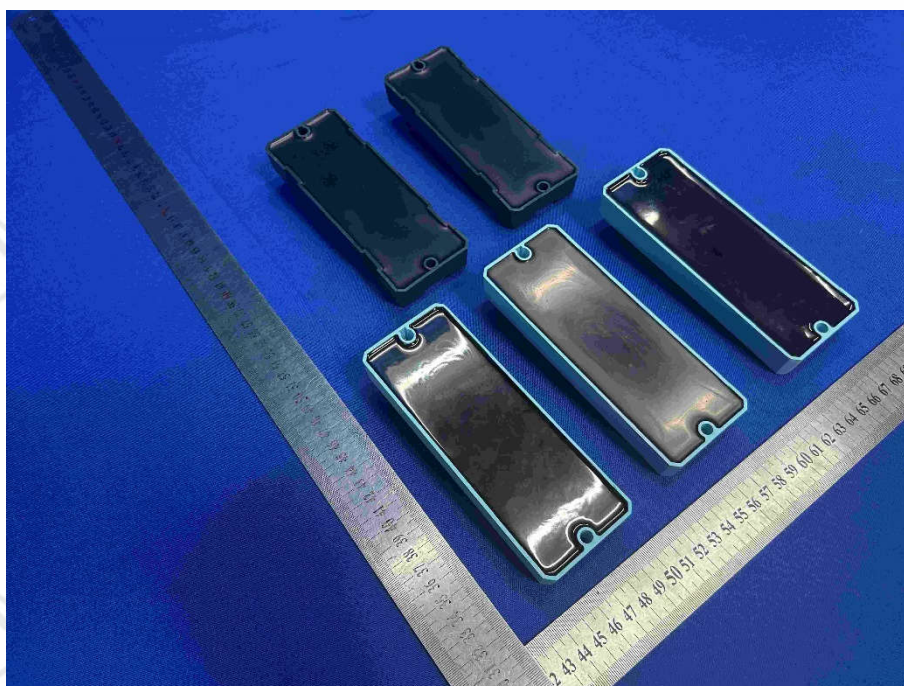
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View Of Product-05



View Of Product-06

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Statement

1. This report is considered invalid without approved signature, special seal and the seal on the perforation;
2. The Company Name shown on Report and Address, the sample(s) and sample information was/were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified;
3. The result(s) shown in this report refer(s) only to the sample(s) tested;
4. Unless otherwise stated, the decision rule for conformity reporting is based on Binary Statement for Simple Acceptance Rule stated in ILAC-G8:09/2019/CNAS-GL015:2022;
5. Without written approval of CTI, this report can't be reproduced except in full;

*** End of Report ***